

Fast switching diode chip in EMCON 3-Technology

FEATURES:

- 600V EMCON 3 technology 70 μm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

- power module
- discrete components



Applications:

- drives
- white goods
- · resonant applications

Chip Type	V_R	I _F	Die Size	Package
SIDC05D60C6	600V	15A	2.37 x 1.9 mm ²	sawn on foil

MECHANICAL PARAMETER:

WECHANICAL PARAMETER.	1			
Raster size	2.37 x 1.9			
Area total / active	4.5 / 2.88	mm ²		
Anode pad size	1.95 x 1.48]		
Thickness	70	μm		
Wafer size	150	mm		
Flat position	180	deg		
Max. possible chips per wafer	3276 pcs			
Passivation frontside	Photoimide			
Anode metallization	3200 nm AlSiCu			
Cathode metallization	Ni Ag -system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500μm			
Reject ink dot size	Ø 0.65mm; max 1.2mm			
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	V_{RRM}		600	V
Continuous forward current limited by	1_		1)	- A
T _{jmax}	I _F			
Maximum repetitive forward current	1		30	
limited by T _{jmax}	/ FRM		30	
Operating junction and storage temperature	$T_{\rm j}$, $T_{ m stg}$		-40+175	°C

¹⁾ depending on thermal properties of assembly

Static Electrical Characteristics (tested on chip), $T_{\rm j}$ =25 °C, unless otherwise specified

Parameter	Symbol	Cond	Value			Unit	
raiailletei	Syllibol	Cond	itions	min.	in. Typ. max.		Oilit
Reverse leakage current	I _R	V _R = 600 V	<i>T_j</i> =25° <i>C</i>			27	μΑ
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	$T_j=25^{\circ}C$	600			V
Forward voltage drop	V_{F}	I _F =15A	<i>T_j</i> =25° <i>C</i>	1.25	1.6	1.95	٧

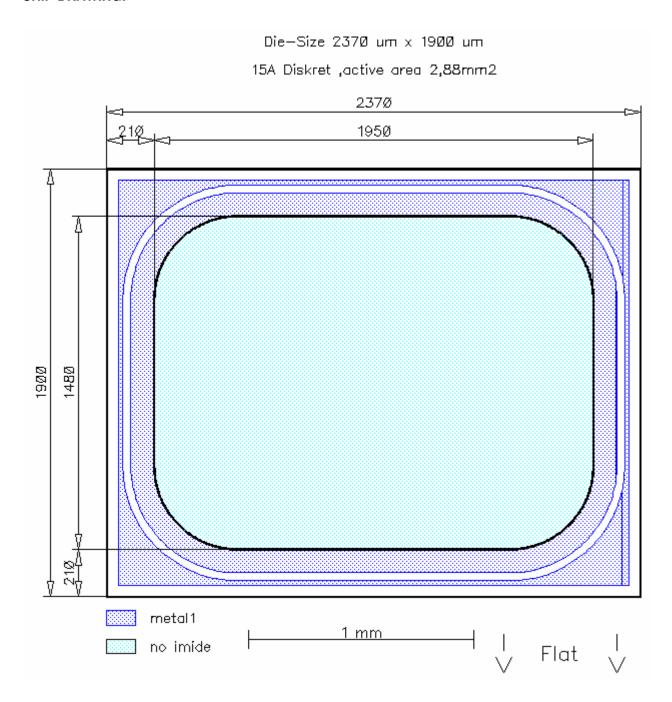
Dynamic Electrical Characteristics (verified by design/characterization), inductive load

Parameter	Symbol	Conditions		Value 2)			Unit
raiailletei	Syllibol			min.	Тур.	max.	
Peak reverse recovery current	I _{RM}	$I_F=15A$ $di/dt=1600A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}C$ $T_j = 125 ^{\circ}C$ $T_j = 150 ^{\circ}C$		23.0 25.0 26.0		A
Recovered charge	Q _r	$I_F=15A$ $di/dt=1600A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}C$ $T_j = 125 ^{\circ}C$ $T_j = 150 ^{\circ}C$		0.80 1.40 1.70		μC
Reverse recovery energy	E _{rec}	$I_F=15A$ $di/dt=1600A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}C$ $T_j = 125 ^{\circ}C$ $T_j = 150 ^{\circ}C$		0.16 0.28 0.37		mJ

²⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





This chip data sheet refers to the device data sheet Description: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883

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Test-Normen Villach/Prüffeld

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